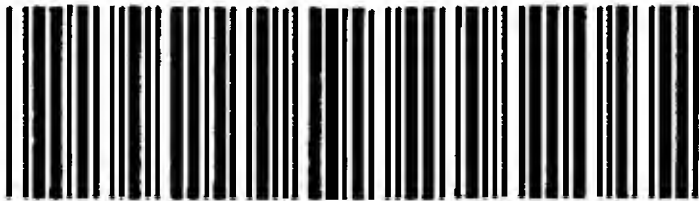


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/801,872	MEEK ET AL.	
	Examiner	Art Unit	
	Benny Q. Tieu	2614	

SEARCHED			
Class	Subclass	Date	Examiner
379	211.01	7/22/2005	BQT
	211.02		
	201.01		
	196		
	127.01		
	142.05		
	93.03		
	142.05		
	114.25		
Updated	Search	12/7/2005	BQT
Updated	Search	5/13/2006	BQT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	7/22/2005	BQT